

1 **Oxidative dissolution of NiO in aqueous electrolyte: an** 2 **impedance study**

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6

7 **Abstract**

8 The present contribution reports on the analysis of the electrochemical properties of
9 screen-printed nickel oxide (NiO) in aqueous electrolyte when NiO is in the
10 configuration of thin film (thickness, $l \leq 7 \mu\text{m}$). This type of NiO samples presents
11 mesoscopic morphology. The latter characteristic combined to the intrinsic
12 electroactivity of the oxide leads to the observation of proportionality between NiO
13 thickness and current density. In particular, NiO undergoes two distinct processes of
14 oxidation with reversible features in aqueous media. These redox processes occur in
15 the solid state and, as such, involve mass/charge transfer between the NiO electrode
16 and the electrolyte. On the other hand, the electrochemical oxidation of NiO is
17 accompanied by the progressive chemical dissolution of the oxide when the latter is
18 in the oxidized state. This is a consequence of the elevated content of stored charge
19 on NiO surface when it interfaces a high polarity solvent like water. In the present
20 work we have considered electrochemical impedance spectroscopy (EIS) for the
21 investigation of the charge transfer/transport properties of NiO during the
22 simultaneous occurrence of chemical and electrochemical processes. The study
23 proposes models of electrical circuits for analyzing the interfacial phenomena
24 involved in the aqueous oxidation of NiO.

25

26 **Keywords:** nickel oxide; electrochemistry; nanostructured electrode; impedance
27 spectroscopy; equivalent circuit

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30 **1. Introduction**

31 Nickel oxide (NiO) is a *p*-type semiconducting material with bandgap width $E_g > 3.5$
32 eV [1]. The interesting electrical transport properties [2–9] combined to its chemical
33 stability [10] and redox photoactivity [11–19] render nickel oxide suitable for a
34 variety of electrochemical applications like energy storage [20–22], electrochromic
35 windows [23–33], solar energy conversion in dye-sensitized solar cells (DSCs)
36 [34,35] and perovskites solar cells [36,37]. Thin films of NiO are electroactive in the
37 solid state and can act then as a charge storage system.[38,39] The diversity of the
38 applicative finalities which NiO is destined to requires the adoption of different
39 methods of preparation. Such a demand of diversification leads to the attainment of
40 NiO in various shapes, morphologies, configurations as well as chemical
41 compositions. Among the various methods of preparation of NiO electrodes for
42 photo-electrochemical applications [13,40–48], we considered screen-printing
43 [15,49], i.e. a method of physical deposition that employs NiO nanoparticles (NPs)
44 dispersed in a spreadable viscous paste as precursor. The main advantages of screen-
45 printing deposition are the scalability and the possibility of depositing uniform and
46 homogeneous films of NiO with nanostructured features onto supporting substrates
47 utilizing a simple and cost-effective experimental set-up. Such a deposition technique
48 affords NiO films with electrical connectivity between the constituent NPs
49 throughout the whole film and warrants the efficacious electrical contact at the
50 NiO/substrate interface[50]. This is because the precursor containing NiO NPs is
51 brought to a temperature sufficiently high (i.e. 450 °C) to sinter the NPs and warrant
52 the electrical percolation between these[51,52]. Such a thermal treatment affords
53 electrodes with nanostructured morphology, large surface area and good mechanical
54 adhesion on a conductive substrate. Due to the spread use of nanostructured
55 cathodes for the water-based (photo)electrochemical applications of water
56 splitting[53–58], and dye-sensitized solar cells with aqueous electrolytes[59–63], it is
57 believed that the fundamental study of the processes of charge transfer and current
58 transport through nanostructured/mesoporous NiO films with thickness $l \leq 7 \mu\text{m}$,

59 [16,17,49] during oxidative chemical dissolution in aqueous electrolytes [16,64,65]
60 would be relevant. As a matter of fact, it is of primary importance to individuate
61 which alterations of the charge transport properties are introduced in nanostructured
62 NiO electrodes under ordinary operative conditions when the electrolyte is
63 protogenic.[59] The analysis of the electrical parameters characterizing the
64 electrochemical behaviour of NiO electrodes would render possible the scrutiny of
65 the ongoing processes of electrochemically induced dissolution of NiO in aqueous
66 electrolyte. In doing so, we have considered the potentiodynamic techniques of cyclic
67 voltammetry (CV)[50] and electrochemical impedance spectroscopy (EIS)[66–68]. In
68 the plethora of works about NiO electrochemistry[69–76] the present study tackles
69 for the first time the problem of how to characterize and model a non homogeneous,
70 mesoscopic electrode of screen-printed NiO when the system is in electroactive state
71 and undergoes an electrochemically activated process of dissolution in aqueous
72 electrolyte. In this context the aspect of anodic evolution of O₂ at NiO electrodes
73 with electrocatalytic features is not considered[77–79].

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79 **2. Experimental Section**

80 *2.1 Preparation of NiO electrodes*

81 The preparation of the NiO paste, i.e. the precursors for screen-printing deposition,
82 has been performed by following the procedural scheme previously reported in ref.
83 17 for paste there denominated P3 (Table 1). All chemicals here utilized were
84 purchased from Sigma-Aldrich or Fluka. The reactants were at the highest degree of
85 purity available and were then employed without any further purification. In brief, the
86 starting mixture is an ethanol solution of NiO nanoparticles (variable diameter, ϕ =
87 20-50 nm), ethylcellulose, α -terpineol and concentrated hydrochloric acid (1 mL).

Step 1	6g of NiO nanopowders are grinded with 1mL of concentrated HCl acid for 5 min (final volume of mixture: 1 mL)
Step 2	Addition of 1mL of H ₂ O to the mixture obtained after Step 1 and grinding for 1 min. This succession is repeated 5 times (final volume of mixture: 6 mL)
Step 3	Addition of 1mL of ethanol to the mixture of Step 2 and grinding for 1 min. This succession is repeated 15 times (final volume of the mixture: 21 mL)
Step 4	Addition of 2.5mL of ethanol to the mixture of Step 3. This succession is repeated 6 times (final volume of the mixture: 36 mL)
Step 5	Transfer of the paste of Step 4 to a beaker using 100 mL of ethanol (final volume of the mixture: 136 mL)
Step 6	The mixture of Step 5 is stirred 1 min, successively sonicated for 2 min and finally stirred again for 1 min
Step 7	Addition of terpineol (20 g)
Step 8	The mixture of Step 7 is stirred 1 min, successively sonicated for 2 min and finally stirred again for 1 min
Step 9	Addition of a solution of ethyl cellulose to the mixture of Step 8. The added solution is formed by adding 3 g of ethyl cellulose in 30g of a 10% v/v solution of ethanol in aqueous solvent
Step 10	The mixture of Step 9 is stirred 1 min, successively sonicated for 2 min and finally stirred again for 1 min. This succession of 4 min is repeated 3 times
Step 11	Slow evaporation of the volatile components of the resulting mixture: The mixture of Step 10 is placed on hot plate at 50°C for 9 hours. After then the NiO nanoparticles paste is cooled down to ambient temperature and ready for being utilized in the screen-printing mode of deposition

88

89 **Table 1.** Procedure of preparation of the precursor-paste utilized to screen-print the
90 electrodes of NiO here characterized.

91

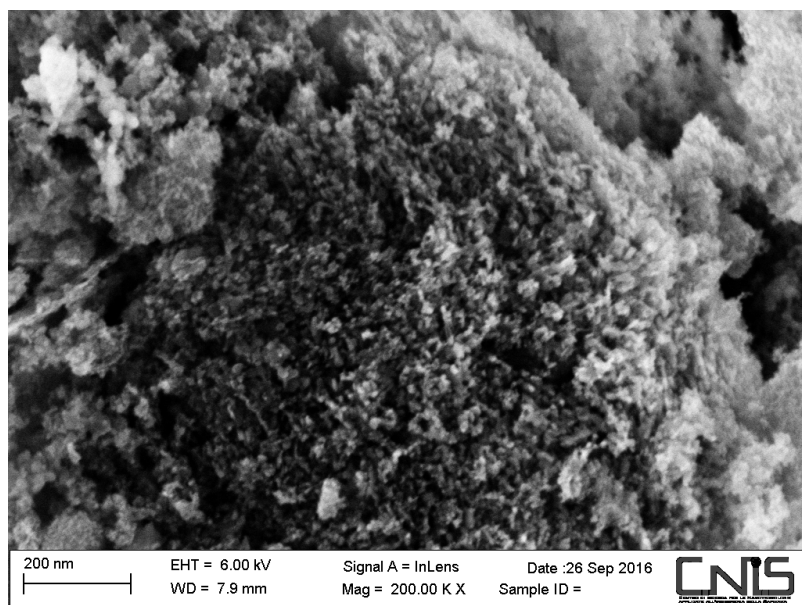
92 The solution thus obtained was slowly heated at 50 °C to give a viscous slurry that

93 could be easily spread onto conductive FTO covered glass panels (item no. TCO227

94 from Solaronix). Paste spreading was done *via* screen-printing through a 90.48 T

95 mesh screen. Prior to paste spreading, the FTO-covered glass panel was cleaned in

96 ultrasonic bath (soapy water, acetone and isopropyl alcohol for 15 minutes each) to
97 remove possible impurities and contaminants adsorbed on the transparent substrate.
98 The as deposited slurry was kept at 110°C in the first 15 minutes of the thermal
99 treatment to remove water molecules eventually adsorbed on the deposited layers. In
100 the second stadium of the thermal treatment the system is brought to the maximum
101 temperature of 450 °C at the rate of 15 °C/min. The deposit is maintained for 30
102 minutes at the chosen value of maximum temperature. At 450 °C the film loses any
103 viscous consistency and sintering of NiO nanoparticles takes place. The selected
104 combination of ramp rate, maximum temperature of processing and duration of the
105 whole thermal treatment allows the creation of a conductive system constituted by
106 NiO with the desired open and nanostructured morphology (Figure 1). Moreover, the
107 adopted thermal treatment prevented also the full coalescence of the nanoparticles.
108 Such an effect would have produced the unwanted deposition of compact films.
109 Sintering of NiO nanoparticles at 450 °C leads to the necking of the NiO
110 nanoparticles. The occurrence of necking allows the formation of a percolation path
111 through which charge carriers deliver the electrical current. The experimental details
112 for the physical characterization of mesoporous NiO electrodes have been reported
113 by our research group in previously published papers [15–17,49,80].



114

115 **Figure 1.** SEM images of the surface morphology of screen-printed NiO electrode
116 ($l = 2 \mu\text{m}$).

117

118 2.2 Electrochemical characterization of screen printed NiO electrodes

119 Screen-printed NiO films on glass/FTO substrates were employed as working
120 electrodes in three-electrode cells. A Pt wire and Ag/AgCl served as counter
121 electrode and reference electrode, respectively. The aqueous electrolyte had the
122 composition 0.2 M KCl, 0.01 M KH_2PO_4 and 0.01 M K_2HPO_4 . In the paper the
123 potential values are referred to the redox couple Ag/AgCl when not differently
124 specified. CVs and EIS profiles were recorded with the potentiostat/galvanostat
125 Autolab PGSTAT12® driven by the Autolab software Nova 1.9. EIS data were
126 recorded within the frequency range $1 \cdot 10^{-1}$ – $1 \cdot 10^5$ Hz with an amplitude of the
127 potential perturbation of 10^{-2} V. The alternating potential we imposed to the cell was
128 applied on going from the highest to the lowest frequency of oscillation. The EIS data
129 were fitted with the software Z-View-3.3 (from Scribner Associates).

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131 3. Results and Discussion

132 3.1 Electrochemical behavior of screen-printed NiO electrodes

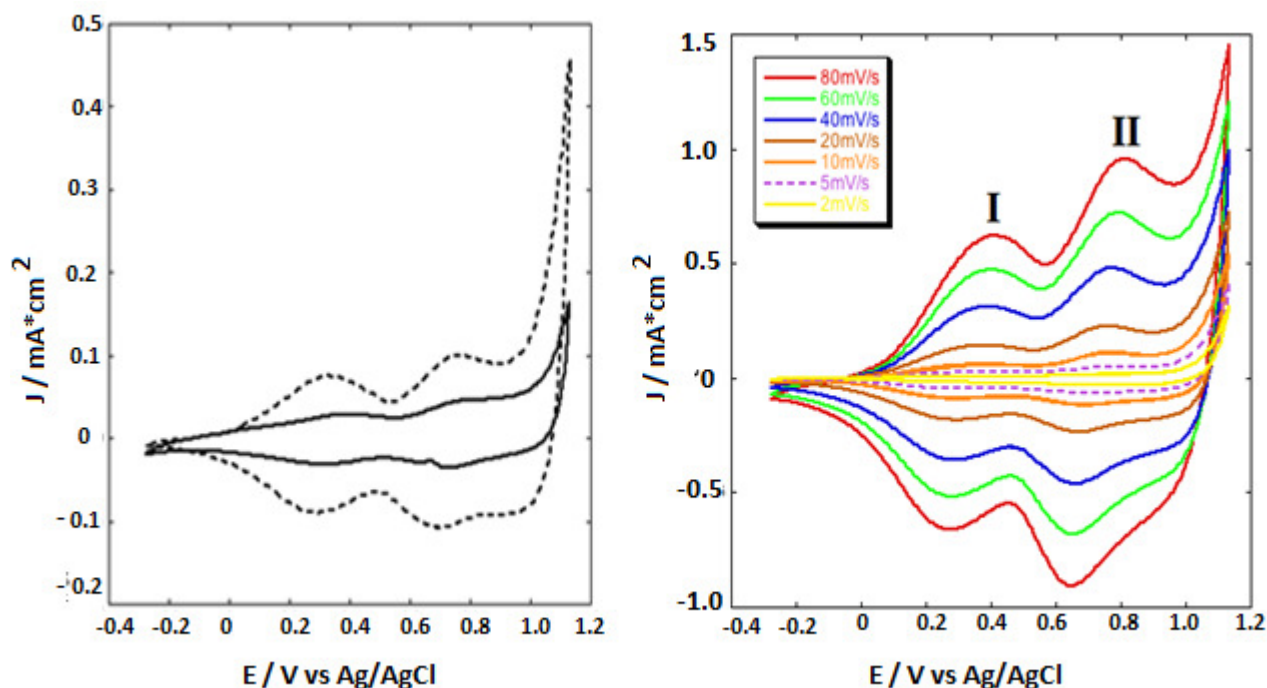
133 The CVs of screen-printed NiO electrodes in water electrolyte presented two broad
134 peaks (Figures 2), as commonly found for mesoporous samples.[13,14,16,17,37]
135 Since the current density is generally proportional to the thickness of mesoporous
136 NiO (Figures 2, left frames and Figure 3, *vide infra*), we evince that screen-printed
137 NiO represents the actual electroactive species that originates the recorded
138 voltamograms. These refer to the solid state oxidation of the NiO electrode
139 according to the processes [40,65,81,82]:

140



143

144 in which pristine NiO in aqueous electrolyte is described as an hydrated systems and
145 the Ni(II) centres are formally oxidized to Ni(III) and Ni(IV) in a consecutive way
146 (succession of Eqs. 1 and 2). These reaction are characteristic of the electrochemistry
147 of NiO in aqueous electrolyte regardless of the method of NiO synthesis/deposition
148 [17,40,83]. The two peaks of NiO oxidation (labelled as **I** and **II** in the right frames
149 of Figures 2) are linear with CV scan rate in aqueous environment.[37] This
150 correlation indicates that the two observed processes of NiO oxidation are surface
151 confined with both oxidized and reduced forms localized on the NiO electrode
152 surface.[84]



153
 154 **Figure 2.** Left: CVs of screen-printed NiO thin films at the scan rate of 10 mV s^{-1}
 155 (full line: $l = 2 \mu\text{m}$; dotted line: $l = 6 \mu\text{m}$). Right: CVs conducted at different scan
 156 rates for the NiO film with $l = 6 \mu\text{m}$. Electrolyte: 0.2 M KCl in water buffered by the
 157 acid-base couple $0.01 \text{ M KH}_2\text{PO}_4 / 0.01 \text{ M K}_2\text{HPO}_4$.

158

159 The amplitude of the current peak is controlled by the surface concentration of Ni(II),
 160 i.e. the starting species of the redox oxidation. The redox process we observe is
 161 characterized by a rate determining step consisting in the oxidation of the Ni(II) sites
 162 localized on the surface of the electrode but not inside the thin film.[47] This is
 163 equivalent to say that the oxidation of Ni(II) does not involve the internal Ni(II)
 164 centers present in the bulk of the mesoporous oxide. This is principally a
 165 consequence of the high repulsive interaction the NiO film would have to sustain if
 166 the charge compensating ions are also inserted in the bulk of NiO and not only
 167 localized on the surface as actually occurs[39]. NiO in the pristine version contains
 168 surface states with Ni(III) centres as predicted by the most common theories on the

169 origin of the interfacial potential at an electrochemical double layer.[85] The Ni(III)
170 centers in pristine NiO are mostly surface localized to compensate the rupture of the
171 symmetry which occurs in passing from bulk to surface[47]. Moreover, surface
172 localized Ni(III) sites stabilize the NiO/electrolyte interface as a consequence of the
173 saturation of the dangling bonds at oxide surface. Along the same voltametric profile
174 the amplitude of peak II is generally higher than that of peak I, regardless the
175 thickness (Figure 3) of the NiO film.[17,40,83] From this finding, we deduce that
176 Ni(III) surface concentration prior to the oxidation step II (Eq. 2) is larger than that of
177 Ni(II) prior to the oxidation step I (Eq.1). Interestingly, the current amplitude of the
178 thicker film is only two times the one of the thinner film. This leads to hypothesize
179 that the thicker is less uniformly porous than the thinner one. At this regard, we
180 determined the charge exchanged by NiO films with different thickness through the
181 integration of the amperometric curves recorded at the potential of first oxidation of
182 NiO when the metal oxide is in contact of an aqueous electrolyte (process I, Figure 2-
183 left frame). Such a determination allows the evaluation of eventual differences of
184 electroactive area per unit thickness of NiO films. Under these circumstances the
185 charge that is exchanged by NiO during its potentiostatic oxidation is not heavily
186 affected by the simultaneous process of chemical dissolution since the dissolved
187 oxidized species based on Ni(III) are not further oxidized during process I (Eq.1).
188 Moreover, the electrochemical process I, i.e. the process of solid state oxidation of
189 NiO at lower potential, is a surface confined process in aqueous electrolyte[40]. As a
190 such, the phenomenon of back diffusion of the dissolved product(s) based on Ni(III)

191 (Eq.1) results to be relatively slow and ineffective on the kinetics of the first
 192 electrochemical oxidation of NiO. The data of integrated charge during first
 193 oxidation of NiO are presented in Table 2.

194

s.r. /mV s ⁻¹	2	5	10	20	40	60	80
<i>l</i> / μm							
2	11.89 (5.94)	11.53 (5.76)	9.17 (4.58)	9.74 (4.87)	10.60 (5.30)	10.50 (5.25)	10.32 (5.16)
6	28.64 (4.77)	22.92 (3.82)	22.92 (3.82)	24.35 (4.06)	26.50 (4.42)	26.26 (4.38)	25.78 (4.30)

195 **Table 2.** Values of charge (Q, in C cm⁻²) exchanged per unit area by screen-printed
 196 NiO electrodes with variable thickness (*l*) during the occurrence of the oxidation
 197 process of Eq.1 (*vide supra*). In parentheses the value of the charge exchanged per
 198 unit area and unit thickness (Q' in C cm⁻² μm⁻¹) of NiO electrode is reported. The
 199 densities of exchanged charge have been calculated at seven different values of scan
 200 rate, s.r., and in potentiostatic conditions when $E_{\text{appl}} = 0.34 \text{ V vs Ag/AgCl}$. The charge
 201 densities NiO exchanges potentiostatically during the first process of oxidation (Eq.1)
 202 are 5.19 and 4.33 C cm⁻² μm⁻¹ for 2 and 4 μm thick film, respectively.

203

204 Data in Table 2 show that the integrated charge depends on both scan rate and film
 205 thickness. The charge exchanged per unit volume of NiO film is generally larger for
 206 the thinner film with respect to thicker one (about 20 % larger) irrespective of the
 207 scan rate. This fact is mainly ascribed to the variation of porosity of the NiO film in
 208 passing from 2 to 6 μm of thickness. Data of Table 2 indicate also unequivocally that
 209 the thinner film of NiO presents the larger surface area with respect to the thicker
 210 sample. This conclusion is somehow supported by the fact that the impedance spectra
 211 of the thinner electrode of NiO are better modelled by an equivalent circuit that

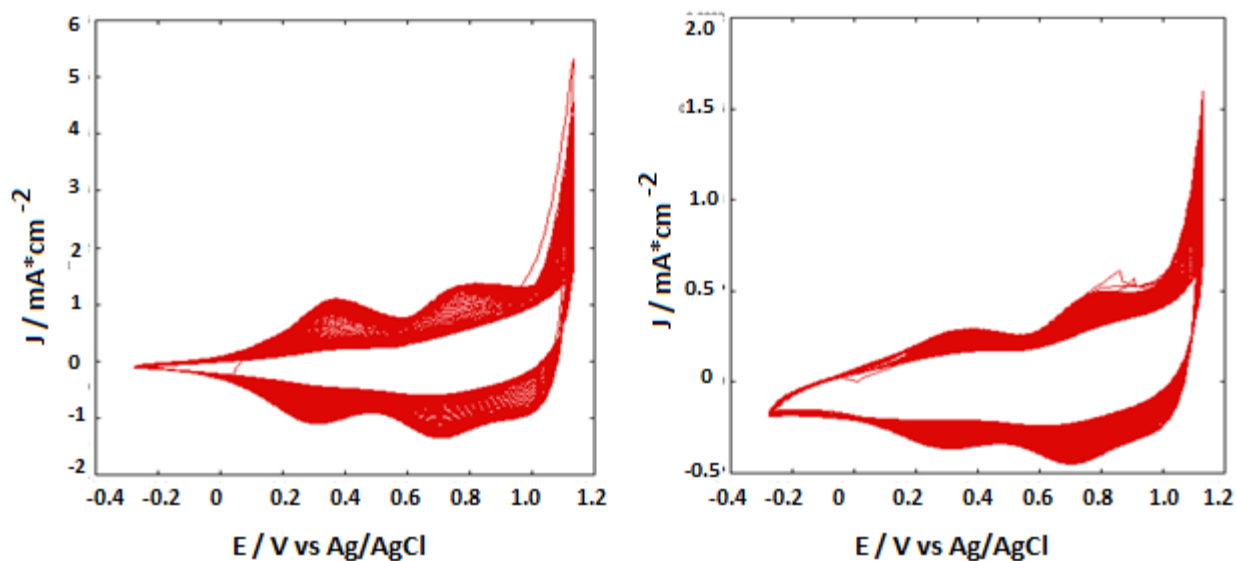
212 includes the electrical parameters of FTO/electrolyte interface. This is equivalent to
213 say that the thinner film of screen-printed NiO does not coat uniformly the FTO
214 substrate (*vide infra*). When the dependence of the integrated charge on scan rate
215 (s.r.) is analysed, a not univocal trend of the charge density Q vs s.r. is observed
216 (Table 2). The maximum value of exchanged charge is determined at 40 mV s^{-1} for
217 both NiO electrodes which differ solely in thickness (Table 2). The existence of an
218 optimum value of exchanged charge indicates that the process I of NiO oxidation is
219 complicated by the occurrence of simultaneous reactions having different kinetics.
220 Since Q (and Q') increases steadily within the s.r. range $5\text{-}40 \text{ mV s}^{-1}$, it is believed
221 that at the lowest scan rates (except 2 mV s^{-1}) the chemical dissolution of mesoporous
222 NiO is fast enough to diminish the amount of electroactive material on the electrode
223 surface when the electrode is under oxidative polarization. This is equivalent to say
224 that a prolonged time of anodic polarization better evidences the occurrence of NiO
225 dissolution. In fact, when screen-printed NiO is kept in a not polarized state and gets
226 immersed in the same electrolyte of the experiments in Figure 2, no
227 detachment/dissolution of NiO is observed. This is confirmed by the overlap of the
228 voltammetric profiles of the NiO electrode previously immersed in the electrolyte and
229 untreated NiO. Therefore, there is no variation of the charge of oxidation for NiO
230 electrodes upon variation of the time of immersion in aqueous electrolyte when NiO
231 is in the not polarized state. When the s.r. exceeds 40 mV s^{-1} the surface and volume
232 densities of exchanged charge diminish again despite of the fact that the durations of
233 anodic polarization of NiO are now shorter with respect to the voltammetries

234 conducted at slower scan rates. The reason of such a behaviour could be ascribed to
235 the kinetic limitation imposed by the movement of charge compensating ions towards
236 the surface of oxidized NiO when the rate of NiO oxidation becomes too high with
237 respect to the rate of migration of the charge compensating ions. At this concern, the
238 mechanism of charge compensation during NiO oxidation would include also the
239 arrival of anions from the electrolyte (as in case of NiO oxidation in non aqueous
240 solvents)[39] in addition to the (relatively faster) removal of protons from the
241 hydrated surface of NiO (Eqs. 1 and 2).

242 As far as the presence of Ni(III) is concerned, its presence in the pristine state of NiO
243 samples has been ascertained by means of X-ray photoelectron spectroscopy (XPS) in
244 a recent study from our group[86]. Such a finding is in accordance with the results
245 obtained from the XPS analysis of mesoporous NiO films deposited via rapid
246 discharge sintering [43,65]. The importance of the acknowledgment of the presence
247 of Ni(III) states in the pristine film of NiO resides on the fact that the Ni(III)/Ni(II)
248 ratio defines the actual stoichiometry of the NiO film and controls its electronic
249 conductivity and optical properties. The Ni(III)/Ni(II) ratio is related to the extent of
250 porosity of the film ($\approx 21.5 \text{ m}^2 \text{ g}^{-1}$ for screen-printed samples)[87] and augments with
251 the increase of NiO surface exposition.

252 The continuous repetition of the electrochemical cycles within the potential range of
253 NiO oxidation in aqueous electrolyte (Figures 3 and 4) gives the progressive
254 dissolution of screen-printed NiO electrode as previously verified with the NiO
255 samples prepared differently[17,64,65]. The electrochemically induced dissolution of

256 NiO is observed as the continuous, progressive thinning of the voltammograms
257 associated to the oxidation of NiO upon repetition of the potential scan.



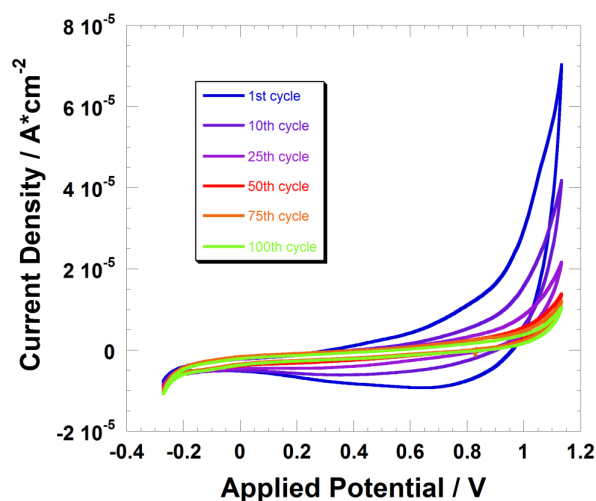
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259 **Figure 3.** First eighty Voltametric cycles of two NiO films obtained via screen-
260 printing. The electroactive electrode of NiO was cycled in the aqueous electrolyte 0.2
261 M KCl buffered by the acid/base couple $\text{H}_2\text{PO}_4^-/\text{HPO}_4^{2-}$. Scan rate: 5 mV s^{-1} . Left
262 plot: $l = 6 \text{ }\mu\text{m}$; right plot : $l = 2 \text{ }\mu\text{m}$.

263

264 Figure 5 shows the comparison of the voltammograms generated by bare FTO and
265 the electrochemically cycled film of screen-printed NiO within the potential range of
266 NiO oxidation. The flatness of the voltammogram of cycled NiO indicates that the
267 electroactivity of this electrochemically modified system is practically identical to the
268 one of bare FTO. Such a finding supports the ascription of the observed phenomena
269 to the occurrence of NiO electrochemical dissolution in aqueous electrolyte without
270 employing the mass-sensitive technique of electrochemical quartz-crystal
271 microbalance which requires the deposition of the electrodes on a substrate made of a
272 proper piezoelectric crystal [88,89].

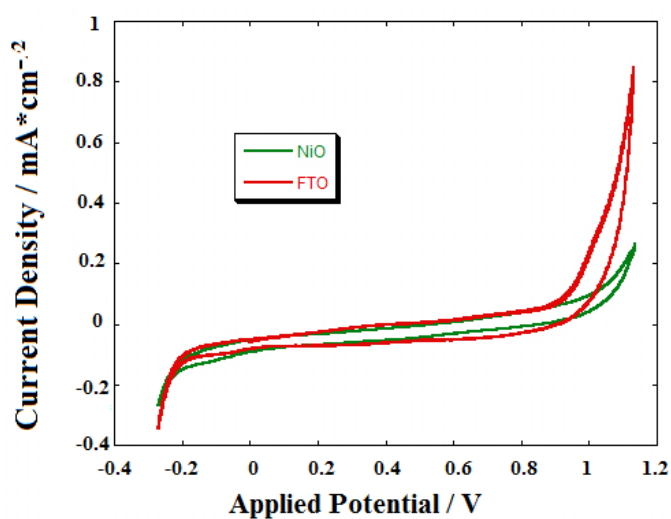
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274

275 **Figure 4.** Selection of Voltametric cycles of a NiO thin film ($l = 2 \mu\text{m}$) obtained via
 276 screen-printing. The electroactive NiO was repetitively cycled in the aqueous
 277 electrolyte 0.2 M KCl buffered by the acid/base couple $\text{H}_2\text{PO}_4^-/\text{HPO}_4^{2-}$. Scan rate: 5
 278 mV s^{-1} .

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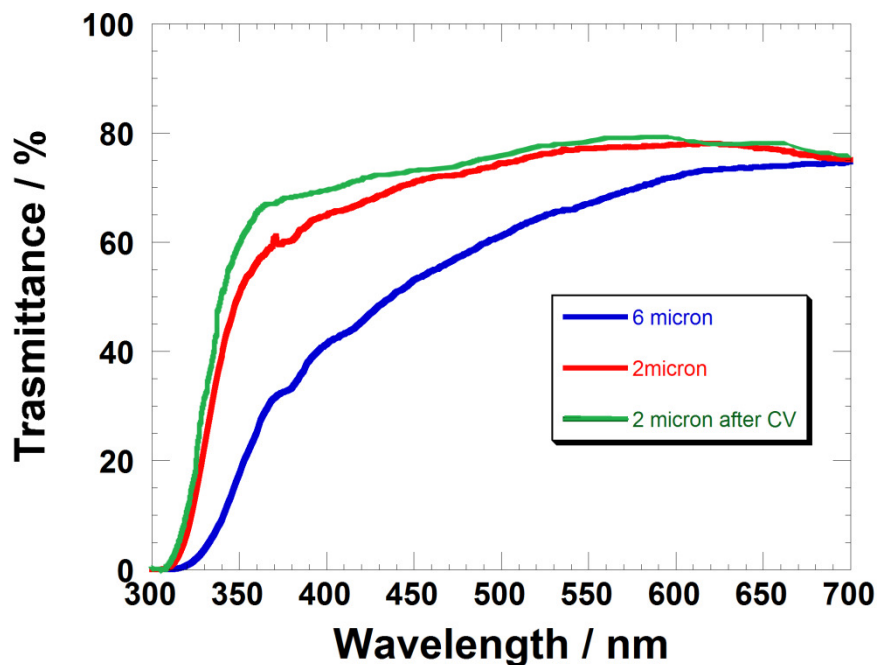
281 **Figure 5.** Comparison of the voltammograms recorded in the same electrolyte of
 282 Figure 4 when the working electrodes are bare FTO (red curve) and screen-printed
 283 NiO after 100 cycles ($l = 2 \mu\text{m}$, green curve). Voltametric responses were recorded at
 284 the scan rate of 5mV s^{-1} .

285

286 As a further confirmation of the effect of electrochemical dissolution of NiO in
 287 aqueous electrolyte the optical transmission spectra of NiO in the pristine and
 288 electrochemically cycled version have been recorded (Figure 6). The comparison of

289 the transmittance curves clearly evidences an effect of thinning for NiO when it
290 undergoes continuous electrochemical cycling in aqueous electrolyte (5 cycles).

291



292

293 **Figure 6.** Comparison of the transmission spectra of NiO at two different thickness
294 values (2 and 6 μm), prior and after the electrochemical cycling in aqueous
295 electrolyte. It is evident a phenomenon of electrochemical dissolution of NiO in
296 passing from pristine to the electrochemically cycled state with the latter having a
297 smaller thickness with respect to the pristine version.

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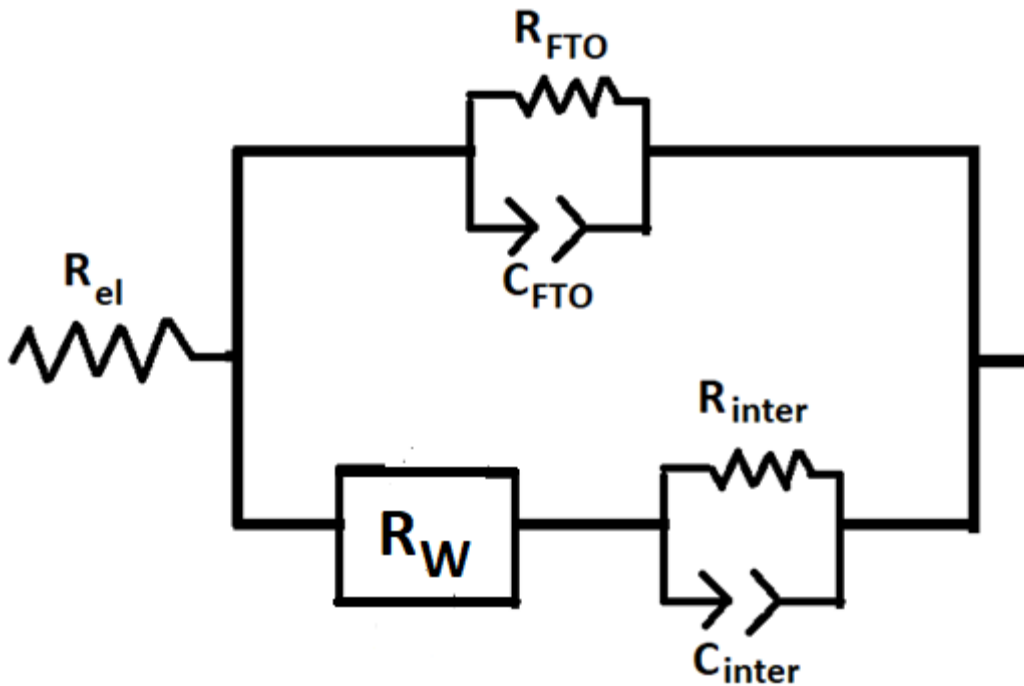
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301 3.2 EIS analysis of screen-printed NiO electrodes

302 During EIS experiment the application of the potential of NiO oxidation does not
303 provoke the dissolution of the NiO film since it has been observed that NiO gets
304 dissolved in aqueous electrolyte upon repeated cycling but not after a single step of
305 oxidation. We have effectuated a sampling of the electrochemical impedance spectra
306 at seven different values of E_{appl} within the applied potential range $-0.2 \leq E_{\text{appl}} \leq 1.1$
307 V vs Ag/AgCl. The impedance spectra of the NiO films have been interpreted in
308 terms of the equivalent circuit depicted in Figure 7[90]. The complete sets of

309 impedance data and the corresponding fitting curves are shown in Figures 8 and 9
310 when $l = 2$ and $6 \mu\text{m}$, respectively. Data are presenting as both Nyquist and Bode plot
311 (Figure 10, phase vs applied frequency). The latter is especially meaningful to
312 evidence the change in the electric properties of the NiO film as a consequence of the
313 polarization.

314



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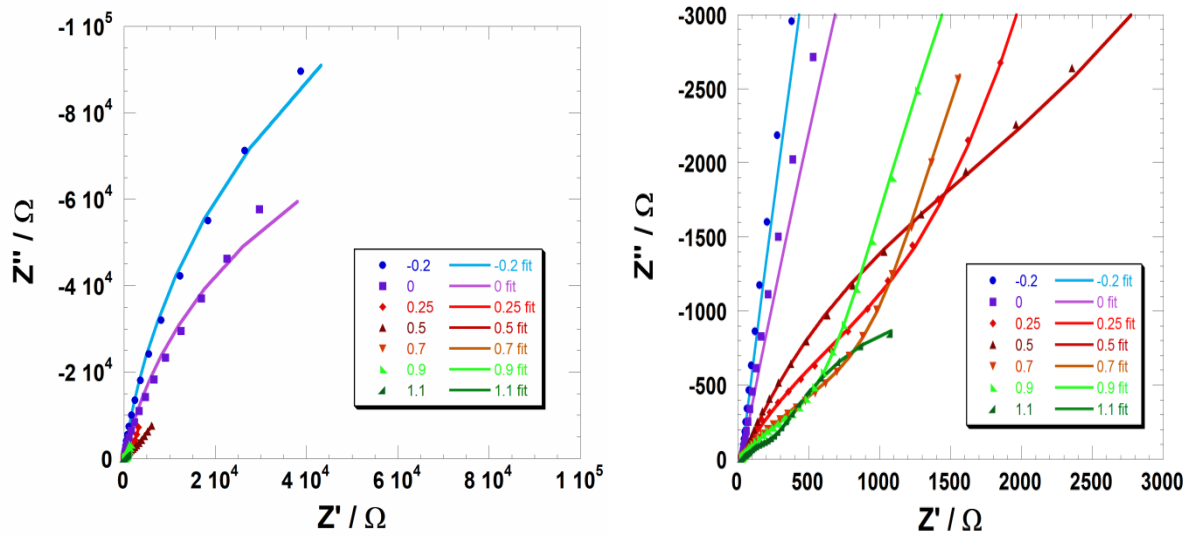
317 **Figure 7.** Equivalent circuit employed for the fit of the impedance spectra of screen-
318 printed NiO (Figures 9 and 10).

319

320

321 In Figure 7, R_{el} represents the sum of the resistance of the electrolyte and the external
322 contacts. This parameter is practically constant (i.e. 20Ω) and does not vary with the
323 variation of applied potential and film thickness. The terms C_{inter} (C_{FTO}) and R_{inter}
324 (R_{FTO}) in Figure 7 refer to the electrical characteristics of the NiO/electrolyte
325 (FTO/electrolyte) interface and indicate respectively the capacitance at the interface
326 and the charge transfer resistance through the same interface. The NiO/electrolyte

327 interfacial charge transfer could be better described as a coupling between a hole in
328 the NiO electrode and an anion coming from the aqueous solution (i.e. hydroxyl
329 anions) as proved by XPS analyses[65]. Anyway, throughout the paper, we will refer
330 to it as a charge transfer process. The FTO/electrolyte interface has been found to be
331 exclusively meaningful for the thinner film. Upon increase of thickness the presence
332 of voids diminishes gradually throughout the film of NiO as evidenced by the
333 analysis of the voltammetries. This brings about a diminution of the chance of
334 creating an extended FTO/electrolyte interface. Moreover, this term became
335 negligible at lower applied potential, i.e. lower than 0.7V vs Ag/Ag⁺ [90], as a
336 consequence of the poor charging of the FTO layer[80]. The terms R_w is the Warburg
337 resistance of the porous film and it should be directly proportional to the amount of
338 stored charge in the NiO film under the different states of polarization. R_w refers to
339 the charge transport/transfer properties of the NiO electrode, i.e. the ohmic resistance
340 associated to the electrical transport through the NiO electrode. In the present case,
341 the Warburg element refers to the diffusion of electronic carriers (i.e. the holes)
342 coupled with counter-anions (i.e. hydroxyl anions) due to the aqueous environment
343 and to the high porosity of the film.



344

345 **Figure 8.** Nyquist plots of the electrochemical impedance spectra for the thinner
 346 screen-printed NiO electrode ($l = 2 \mu\text{m}$). Left: complete spectrum of impedance.
 347 Right: zoom of the impedance spectra in the range $0 \leq Z' \leq 3000 \Omega$ and $-3000 \leq Z'' \leq$
 348 0Ω . Spectra have been recorded at $E_{\text{appl}} = -0.2, 0.0, 0.25, 0.5, 0.7$ and 0.9 V vs
 349 Ag/AgCl . The continuous curves represent the fitting curves whereas the dots are the
 350 experimental points. Fits have been obtained with the equivalent circuit of Figure 7.
 351 The corresponding fitting parameters are shown in Table 3.

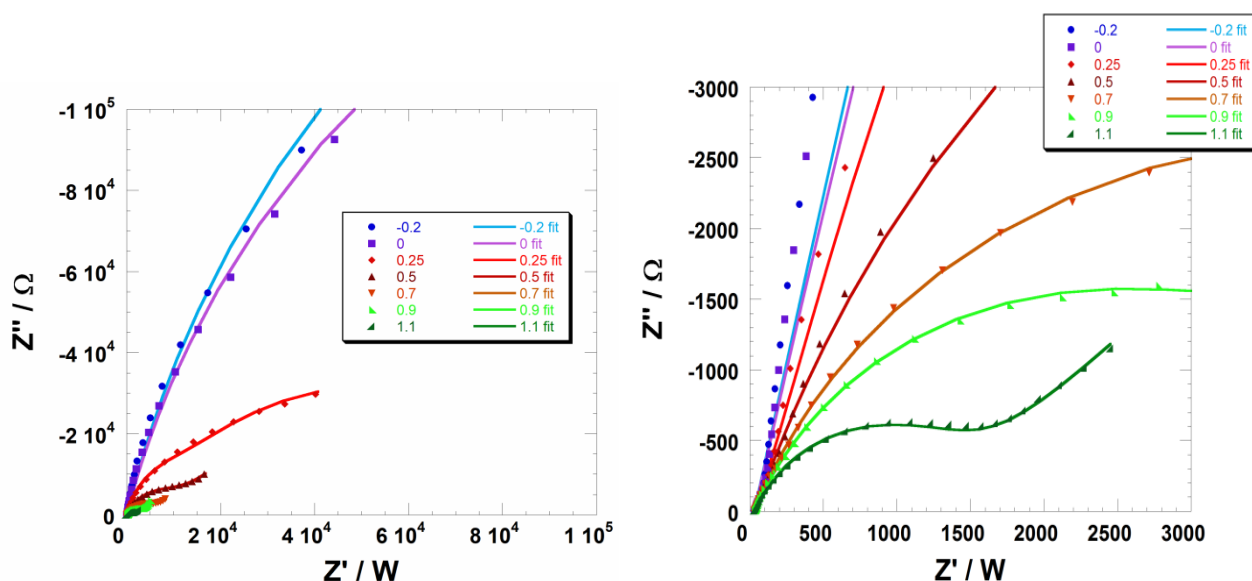
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353 The pure capacitance element C_{inter} (Figure 7) is actually considered as a constant
 354 phase element (CPE), i.e. a term which allows an easier fit of the experimental data
 355 without influencing the reliability of the obtained parameters. The actual capacitance
 356 (C_{real}) could be calculated applying the following equation:

$$C_{\text{real}} = \frac{(C_{\text{CPE}} * R)^{\left(\frac{1}{n}\right)}}{R}$$

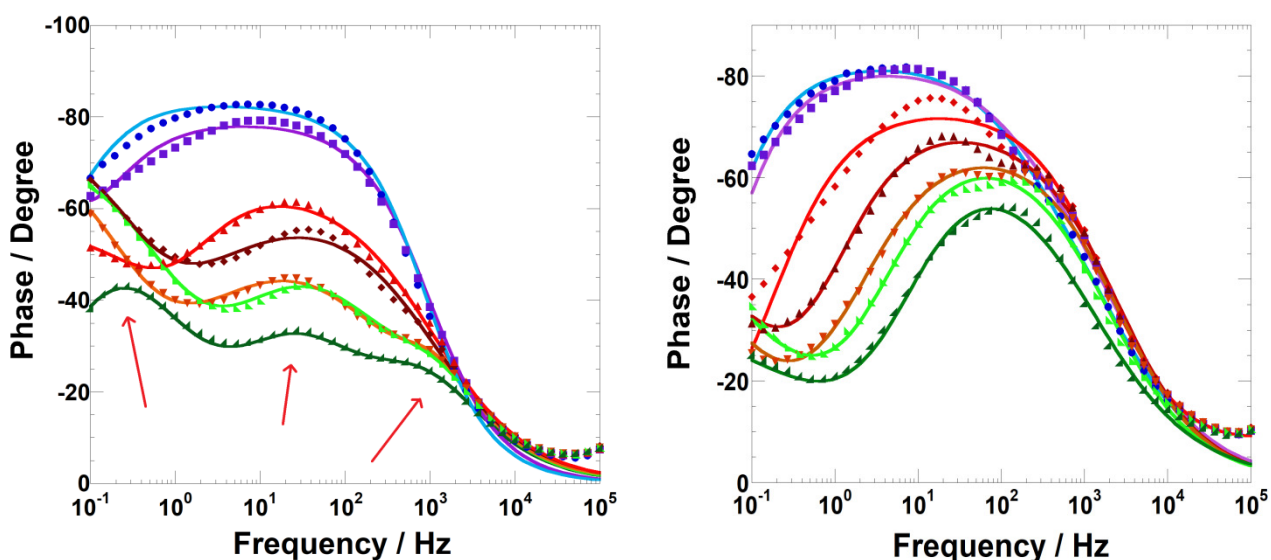
357 Where C_{CPE} and n are the two parameters constituting the CPE element and R is the
 358 value of the resistance associated to the latter. If n is equal to 1, the CPE acts a pure
 359 capacitive element. When the applied potential is lower than the NiO valence band
 360 edge, the electrode is expected to behave as an insulating film (R_{w} tends to infinite

361 values) and only the impedance features of the non-ohmic resistance of the
 362 NiO/aqueous electrolyte interface are observed.



363
 364 **Figure 9.** Nyquist plots of the electrochemical impedance spectra for the screen-
 365 printed NiO electrode ($l = 6 \mu\text{m}$). Left: complete spectrum of impedance. Right:
 366 zoom of the impedance spectra in the range $0 \leq Z' \leq 3000 \Omega$ and $-3000 \leq Z'' \leq 0 \Omega$.
 367 Spectra have been recorded at $E_{\text{appl}} = -0.2, 0.0, 0.25, 0.5, 0.7$ and 0.9 V vs Ag/AgCl .
 368 The continuous curves represent the fitting curves whereas the dots are the
 369 experimental points. Fits have been obtained with the equivalent circuit of Figure 7.
 370 The corresponding fitting parameters are shown in Table 4.

371
 372 Bode plots (Figure 10) display the dependence of the phase of the impedance on
 373 applied frequency. This way of representing the EIS data helps to clarify the kinetic
 374 features of the electrical transport through NiO. In particular, three different peaks
 375 could be distinguished in the EI spectra of the cell with the thinner NiO electrode
 376 whereas a thicker electrode generates only one broad peak upon increase of applied
 377 potential. The two additional peaks characteristic of the thinner electrode are ascribed
 378 to the process of charge transfer occurring at the FTO/electrolyte interface.



379

380 **Figure 10.** Bode plots of the cells with the (left) thinner and (right) thicker working
 381 electrode of NiO. In the left frame the three red arrows indicate the peaks in
 382 correspondence of which transitions between states with different transport properties
 383 take place.

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387 The fitting values of the electrical elements constituting the equivalent circuit of

388 Figure 7 are listed in Tables 3 and 4 when NiO working electrode was 2 and 6 μm

389 thick, respectively. With regard to the thinner film of NiO ($l = 2 \mu\text{m}$), the values of

390 R_{FTO} and C_{FTO} could be defined when the applied potential exceeds the threshold of

391 0.7 V vs Ag/AgCl (Table 1). When $E_{\text{appl}} < 0.7 \text{ V vs Ag/AgCl}$ the FTO/electrolyte is

392 not relevant since the FTO layer is not sufficiently charged to start an event of charge

393 transfer through its interface with the electrolyte. R_{FTO} and C_{FTO} vary in an opposite

394 way with respect to E_{appl} , with $R_{\text{FTO}}/C_{\text{FTO}}$ increasing/decreasing upon potential

395 increase (Table 3). These findings would indicate that the FTO substrate does not

396 behave exclusively as a polarisable electrode when NiO oxidation starts otherwise

397 C_{FTO} would have been invariant.

$E_{\text{appl}} /$ V vs Ag/AgCl	-0.20	0.00	0.25 V	0.50	0.70	0.90	1.10
R_{FTO} / Ω	-	-	-	-	12.7 ± 0.3	15.7 ± 0.2	33.6 ± 0.2
$C_{\text{FTO}} / \mu\text{F}$	-	-	-	-	64 ± 5	32 ± 3	14 ± 1
$R_{\text{inter}} / \Omega$	106340 ± 4533	35182 ± 943	1848 ± 175	1693 ± 158	923 ± 93	492 ± 74	203 ± 44
$C_{\text{inter}} / \mu\text{F}$	18 ± 3	23 ± 4	45 ± 6	56 ± 8	77 ± 15	87 ± 23	112 ± 25
$R_{\text{W}} / \text{k}\Omega$	257 ± 1	135 ± 1	27.0 ± 0.8	12.6 ± 0.5	8.6 ± 0.4	7.2 ± 0.2	2.7 ± 0.1

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Table 3. Fitting values of the variable electrical parameters relative to the EIS data of NiO electrode ($l = 2 \mu\text{m}$) at various values of applied potential. In the first row E_{appl} is expressed in V vs Ag/AgCl. The adopted model is the one depicted in Figure 7.

$E_{\text{appl}} /$ V vs Ag/AgCl	-0.20	0.00	0.25	0.50	0.70	0.90	1.10
$R_{\text{inter}} / \Omega$	146340 ± 7533	57136 ± 6123	25724 ± 2657	8548 ± 669	5580 ± 397	3737 ± 225	1238 ± 84
$C_{\text{inter}} / \mu\text{F}$	21 ± 4	25 ± 3	97 ± 8	133 ± 12	174 ± 32	222 ± 21	240 ± 48
$R_{\text{W}} / \text{k}\Omega$	283 ± 1	144 ± 1	57.0 ± 2.8	27.6 ± 1.5	18.5 ± 1.2	14.8 ± 0.4	4.4 ± 0.3

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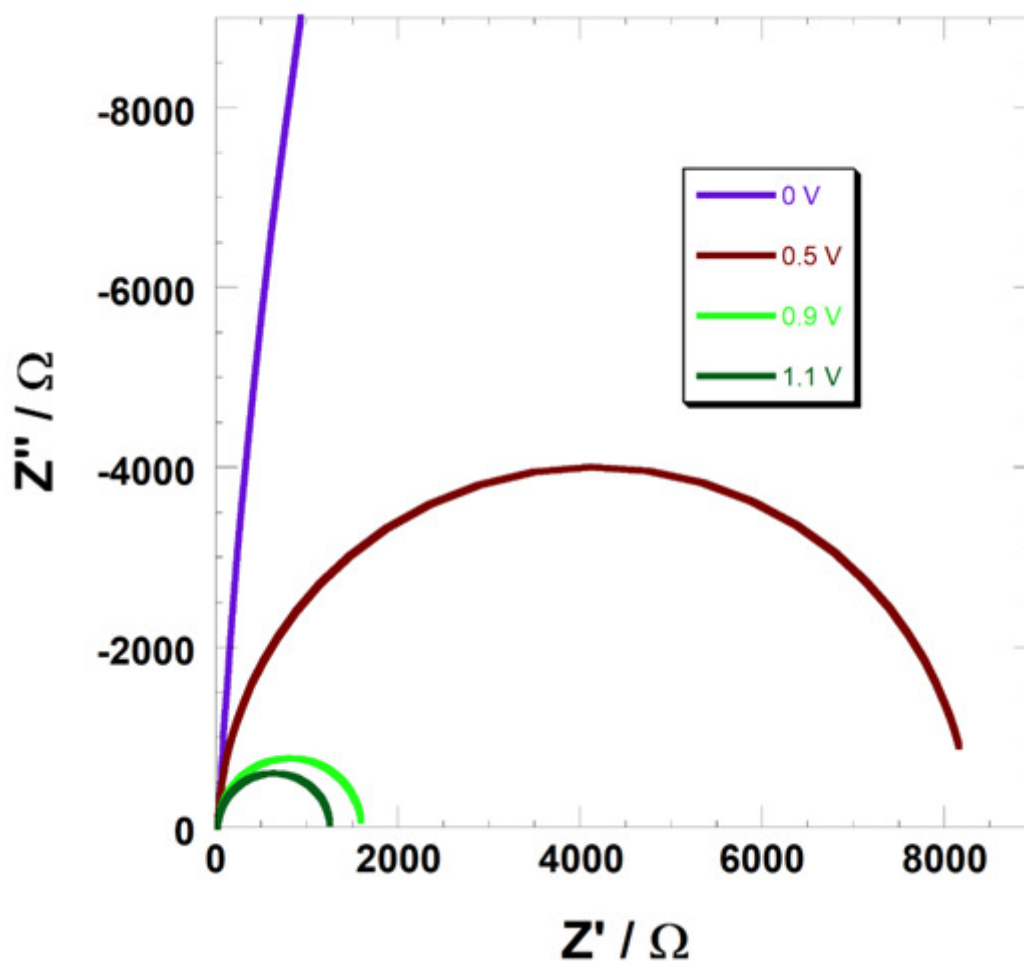
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Table 4. Fitting values of the variable electrical parameters relative to the EIS data of NiO electrode ($l = 6 \mu\text{m}$) at various values of applied potential. In the first row E_{appl} is expressed in V vs Ag/AgCl. The adopted model is the one depicted in Figure 7.

412 Moreover, the increase of R_{FTO} with the increase of E_{appl} (and the concomitant
413 acceleration of NiO oxidation) indicates that FTO is involved in a process of charge
414 transfer that is inhibited by the onset of the oxidation of NiO. At this concern we have
415 considered the analysis of the electrochemical impedance spectra of bare FTO
416 (Figure 11).



417

418 **Figure 11.** Nyquist plots of the electrochemical impedance spectra for bare FTO.
419 when $E_{\text{appl}} = 0.0, 0.5, 0.9$ and 1.1 V vs Ag/AgCl.
420

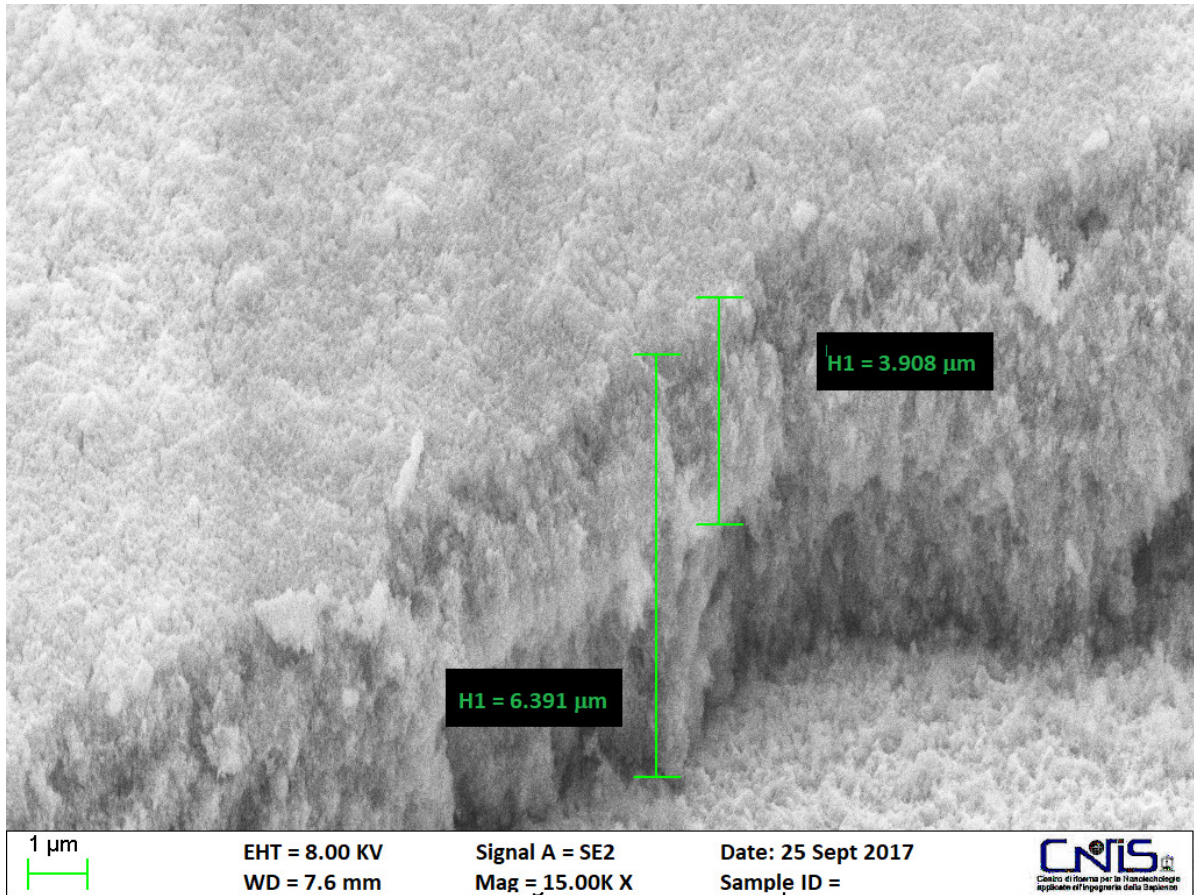
421 Upon fitting of the experimental data in Figure 11 we found that the charge transfer
422 resistance of bare FTO actually decreases with the applied potential being $R_{\text{FTO}} =$

423 1235, 1536, 8265 and 193324 Ω when E_{appl} is respectively 1.1, 0.9, 0.5 and 0.0 V vs
424 Ag/AgCl. The trend of the interfacial capacitance is discordant with the one of R_{FTO}
425 being $C_{\text{FTO}} = 43, 40, 21$ and $3 \mu\text{F}$ respectively for $E_{\text{appl}} = 1.1, 0.9, 0.5$ and 0.0 V vs
426 Ag/AgCl. The charge transfer resistance of bare FTO is clearly larger than the one of
427 NiO-coated FTO since NiO is known for having an electrocatalytic effect towards
428 oxidative processes with respect to FTO[12].

429 As far as the resistive terms R_{inter} and R_{W} are concerned, both these terms decrease
430 with the applied potential. This is consistent with the increase of the concentration of
431 electronic and ionic charge carriers in the oxide film with the progress of oxidation on
432 going from -0.2 to 1.1 V vs Ag/AgCl. Such a trend is common for both of NiO
433 samples. The capacitive term C_{inter} depends directly on the amount of charge at the
434 NiO/electrolyte surface. The observation of the increase of C_{inter} with E_{appl} is then
435 largely expected. A very large increase of both R_{W} and R_{inter} is determined when the
436 applied potential goes from 0.25 to 0 V vs Ag/AgCl. This is probably due to a change
437 in the electronic nature of the NiO film: at applied potential lower than 0.25 V vs
438 Ag/AgCl, the polarization superimposed on the electrode causes the filling of the
439 surface-localized holes (onset of NiO reduction)[13,14] and the NiO film becomes
440 more insulating upon the neutralization of these defective sites localized on NiO
441 surface. As previously stated, R_{W} is mainly controlled by the amount of stored charge
442 in the electrode and a decrease of the stored charge is associated with a lower value of
443 R_{W} . The transition from a semiconducting state to an insulating one is not sharp and
444 for the attainment of an insulating state of NiO more negative potential values need to

445 be applied. On the other hand, in aqueous environment the molecular hydrogen
446 evolution reaction takes place at applied potential lower than -0.2 V vs Ag/AgCl and
447 prevents the attainment of insulating NiO upon electrochemical polarization.
448 Anyway, the transition semiconductor/insulator is somewhat supported by the
449 remarkable decrease of the interfacial capacitance of the film upon diminution of the
450 applied potential (Tables 3 and 4). The fitting parameters have a common trend with
451 E_{appl} for both values of NiO film thickness. The thicker film results more resistive
452 than the thinner. This is somewhat unexpected since an increase of electrode
453 thickness should lead to a larger exposed surface and a higher amount of charge
454 exchanged by the oxidized electrode when the electrode is homogeneously
455 mesoporous throughout the whole thickness. It has been previously observed that
456 screen-printed NiO electrodes are not homogeneously porous if the thickness exceeds
457 3-4 μm [87] A 6 μm -thick film of screen-printed is expected to be a sequence of layers
458 differing in porosity with the layers of more open morphology located nearer the FTO
459 substrate and the more compact layers positioned at the interface with the electrolyte.
460 This lack of homogeneity would explain also the decrease of the volume density of
461 the charge exchanged by the NiO electrode in passing from the thinner to the thicker
462 film (*vide supra*). The FE-SEM image of the cross-section of the thicker film of NiO
463 (Figure 12) reveals that the electrode is formed by the superposition of an upper
464 compact layer (with thickness of about 2.5 μm) and a porous (and thicker) layer with
465 approximate thickness of $\sim 3.9 \mu\text{m}$.

466



467

468 **Figure 12.** FE-SEM image of the cross section of screen-printed NiO electrode ($l =$
 469 $6\mu\text{m}$).

470

471 The observation of such a morphology justifies the higher resistivity of the thicker
 472 film with respect to the thinner. In an aqueous environment, the holes that traverse
 473 the NiO film are coupled with the hydroxyl anions with consequent formation of a
 474 system with mixed conduction[91]. Such a mechanism retains its validity regardless
 475 of film thickness. If the film possesses variable morphology with porous layers
 476 adjacent to more compact layers, the flow of the charge carriers in the mixed
 477 conduction regime will results more hindered in correspondence of the compact
 478 layers. A uniformly porous film of oxidized NiO can drain the charge-compensating
 479 hydroxide anions (in case of an aqueous electrolyte) externally on its surface

480 throughout the whole layer of NiO due to the electric field of the holes which move
481 within oxidized NiO. In presence of a compact layer of NiO the charge compensating
482 anions cannot move along the NiO/electrolyte interface through the whole thickness
483 of the film. As a consequence of this physical limitation, the thicker film of NiO with
484 compact features displays a larger electrical resistance with respect to the thinner
485 film. When $E_{\text{appl}} < 0 \text{ V vs Ag/AgCl}$, NiO behaves as an insulating material and in this
486 case the electrical properties of charge transport are practically insensitive to the
487 differences in morphology. The thinner film is then as resistive as the thicker one and
488 the characteristic of NiO morphology becomes crucial exclusively when NiO has to
489 sustain a current, i.e. in the semiconducting state for $E_{\text{appl}} > 0.1 \text{ V vs Ag/AgCl}$.

490 From the comparison of the values in Tables 3 and 4 it results that R_{inter} is generally
491 higher for the thicker film. This is a consequence of the presence of a more extended
492 portion of compact layer in the thicker electrode with respect to thinner one. There is
493 a correlation between R_{inter} and R_{W} since a high value of R_{inter} provokes charge
494 accumulation on electrode surface that renders harder the further charge transport
495 through the interface and successively through the NiO film. This hypothesis is
496 supported by the generally higher values of C_{inter} for the thicker electrode with respect
497 to the thinner electrode for any value of NiO polarization within the range of
498 potential here examined. Again, the electrical parameters tend to assume the same
499 values for the NiO films differing in thickness (and morphology) when null or
500 negative values of potential are applied and charge transport phenomena are
501 inhibited.

502

503 **4. Conclusions**

504 Nanostructured NiO electrodes in the configuration of thin films ($l < 7 \mu\text{m}$) were
505 prepared via screen-printing of precursor paste and the electrochemical properties
506 were studied in aqueous solution. In this electrolytic ambient NiO manifests two
507 reversible processes of solid state oxidation within the potential range 0.1 - 1.0 V vs
508 Ag/AgCl. The kinetics of these electrochemical processes resulted controlled by a
509 step confined on the electrode surface. Continuous electrochemical cycling brings
510 about the dissolution of these nanoporous NiO films as verified by the progressive
511 decrease of the current exchanged by NiO upon cycling and by the decrease of
512 optical absorption of the film on going from the pristine to the electrochemically
513 cycled state. The electrochemical oxidation brings about a general diminution of the
514 intrinsic electrical resistance of screen-printed NiO as revealed by the analysis of the
515 electrochemical impedance spectra. The combined analysis of the morphological
516 characteristics and of the impedance spectra of NiO electrodes has shown that screen-
517 printed electrodes present a non homogeneous porosity when NiO films are thicker
518 than $4 \mu\text{m}$. NiO film thickening brings about an increase of film compactness (or
519 decrease of porosity). Such a morphological feature of the thicker films is
520 accompanied by larger values of both resistive terms (interfacial and bulk) and
521 double layer capacitance with respect to the thinner film with $l < 3 \mu\text{m}$. In particular,
522 the $2 \mu\text{m}$ thick film of NiO obtained via screen-printing is porous throughout the
523 whole thickness and does not cover uniformly the FTO substrate. The last conclusion

524 has been drawn for the necessary inclusion of the electrical features of the
525 FTO/electrolyte interface for the simulation of the electrochemical impedance spectra
526 of thinner NiO films.

527

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